



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

**CHEN, KAI et al.**

Group Art Unit: **2877**

Serial No.: **10/002,000**

Examiner: **Vincent P. BARTH**

Filed: **December 5, 2001**

P.T.O. Confirmation No.: **2814**

FOR: **AXIS DETERMINATION APPARATUS,  
FILM-THICKNESS MEASUREMENT APPARATUS,  
DEPOSITION APPARATUS, AXIS DETERMINATION  
METHOD, AND FILM-THICKNESS MEASUREMENT METHOD**

**AMENDMENT UNDER 37 CFR §1.111**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

November 25, 2003

Sir:

In response to the Office Action dated **August 29, 2003**, please amend the above-identified application as follows:

RECEIVED  
DEC - 1 2003  
PTC 2800 MAIL ROOM